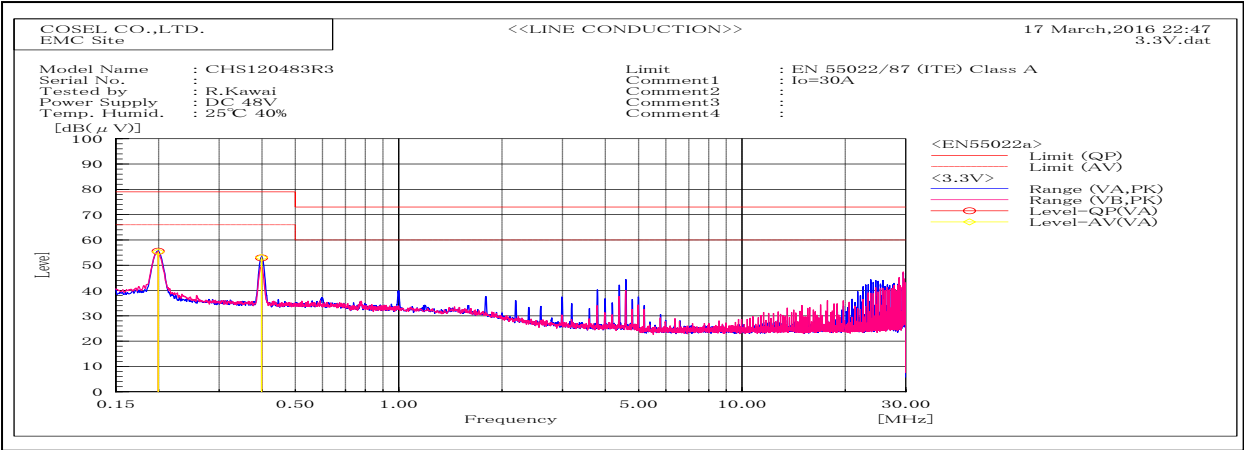
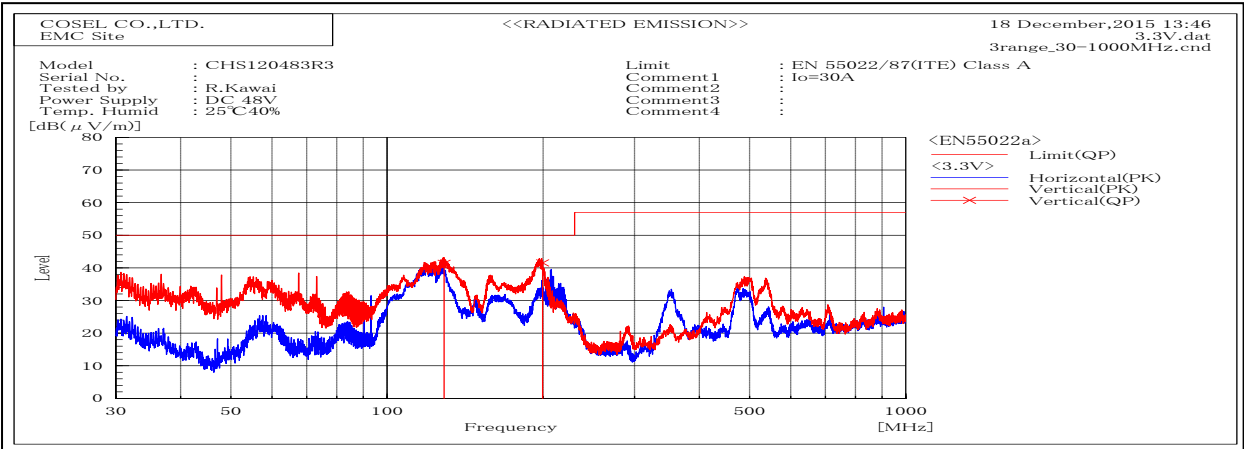


DATA SHEET		Date	06-May-16
Model	CHS120483R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai



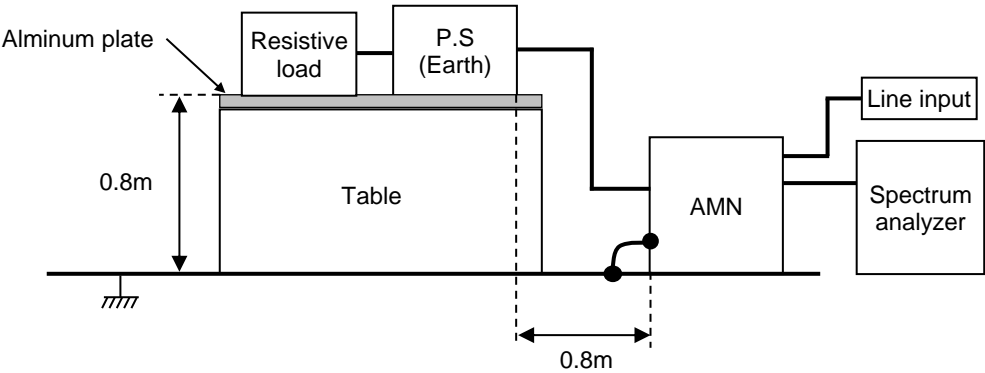
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.199		VA	35.4	35.3	20.1	55.5	55.3	79	66	23.5	10.7	Pass	
0.399		VA	32.9	32.8	20	52.9	52.7	79	66	26.1	13.3	Pass	



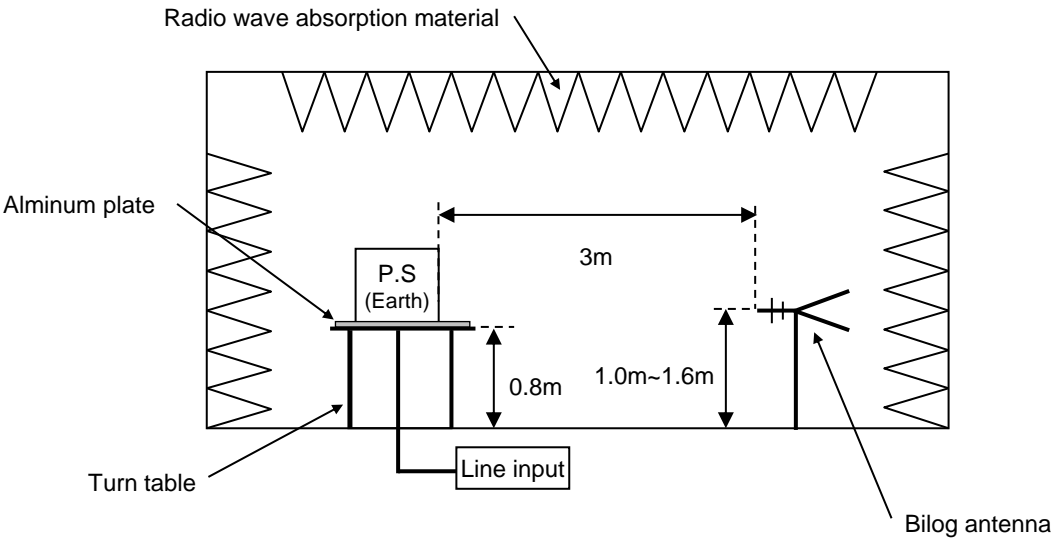
Frequency MHz	Harm	Polarization	Stability	Reading dB(μV)		Factor dB(1/m)	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
				QP	AV		QP	AV						
128.829		V	Stable	59.0		-17.6	41.4		50.0	8.6	Pass	132.0	93.0	
199.508		V	Stable	57.3		-15.8	41.5		50.0	8.5	Pass	113.0	4.0	

DATA SHEET		Date	06-May-16
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai

1. Line conduction



2. Radiated emission



## Conditions

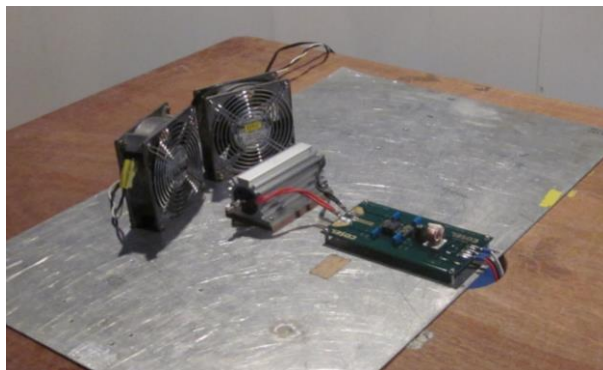
Test : EMI  
Model Name : CHS12048□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

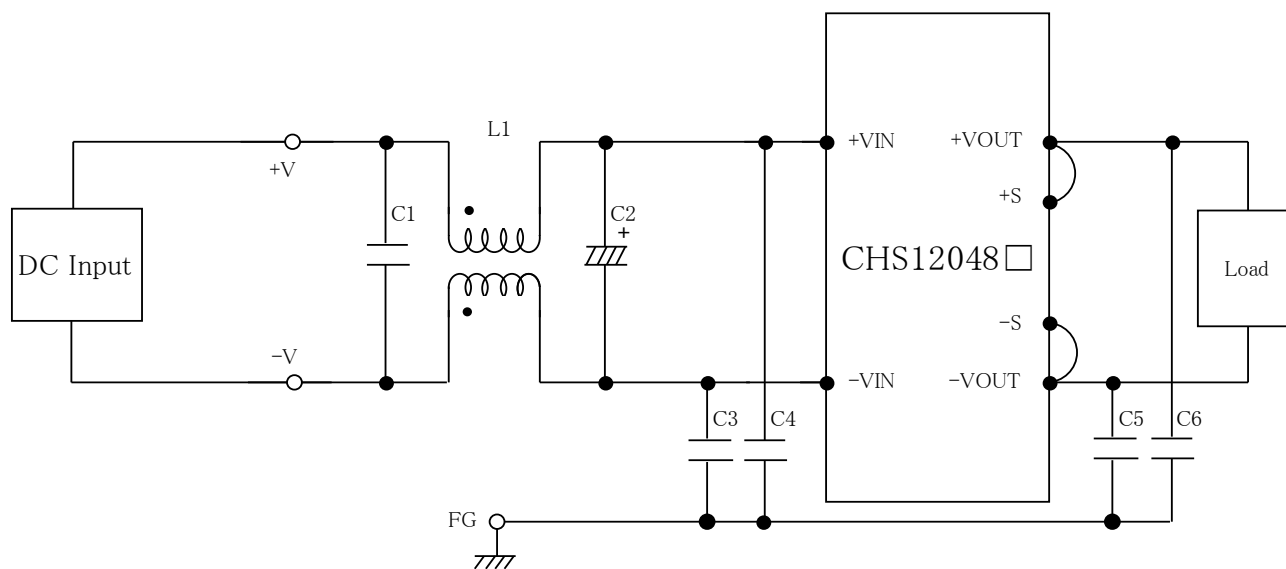


Fig.1 Testing circuitry

L1 : 1mH SC-05-10J (TOKIN)  
C1 : 250V 2.2  $\mu$ F FPD22E225J4 (NITSUKO)  
C2 : 100V 47  $\mu$ F PWseries (nichicon)  
C3,C4 : 630V 0.068  $\mu$ F FPD22J683J4 (NITSUKO)  
C5,C6 : 630V 0.033  $\mu$ F FPD22J333J4 (NITSUKO)